

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/812,526	LEE ET AL.	
	Examiner	Art Unit	
	David J. Makiya	2875	

**SEARCHED**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**